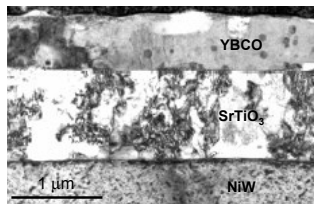


All Solution Deposited YBCO/SrTiO₃/NiW Coated Conductors

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October 31, 2006
ISS 2006, Nagoya, Japan

Sandia is a multiprogram laboratory operated by Sandia Corporation, a Lockheed Martin company, for the US DOE NNSA, under contract DE-AC04-84AL85000



Outline

All Solution Deposited 2nd Generation Coated Conductors

Motivation: robust materials and reproducible processing of YBCO tapes

Growth of solution-deposited buffer layers

- material selection
- growth atmosphere
- control of film texture/avoiding random nucleation
 - use of seeded nucleation & liquid phases
- effect of buffer layer thickness (80 nm – 1 μm)

Solution-deposited YBCO for continuous coating

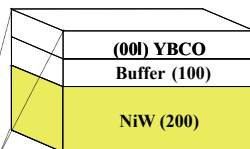
- limitations of single layer thickness: control of stresses
- control of Cu volatility
- single layer optimization: 0.3 μm or 0.7 μm
- multilayer deposition

Summary

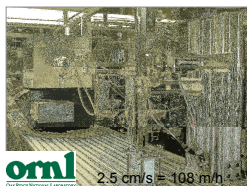
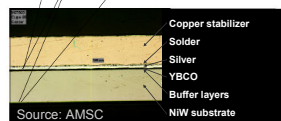


Schematic

Goal: all-MOD 2nd Generation Coated Conductors



Ideal situation:
Simplified structure
Behavior approaching PLD
RABiTS or IBAD MgO
High linear production speeds



Functional roles of composite layers

Substrate

- (100) substrate cube texture
- Must be handleable

↓ O₂, ≥ 740°C

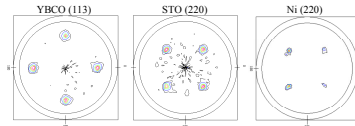
YBCO (001)	3.82 Å
Buffer (100)	3.5-4.2 Å
NiW (200)	3.52 Å

Buffer Layer

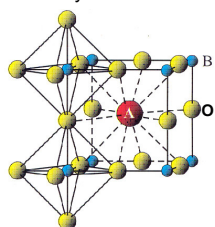
- Lattice match substrate (currently Ni-5%W)
- Provide smooth, (100) epitaxial template for YBCO
- Suppress oxidation of substrate metal

YBCO

- High structural perfection
- Maintain properties to 1-2 μm thickness



Candidate buffer layers - courtesy M. Paranthaman



Ideal ABO₃ Perovskite Structure showing the Octahedral and 12-fold co-ordination of B and A-site cations

Material	Lattice parameter (pseudo cubic) Å	% lattice mismatch vs. YBCO	% lattice mismatch vs. Ni	Property
BaCeO ₃	4.377	13.55	21.59	Insulator
BaZrO ₃	4.193	9.27	17.34	Insulator
SrRuO ₃	3.941	3.08	11.17	Metal
SrTiO ₃	3.905	2.16	10.26	Insulator
SrTi(Nb)O ₃	3.905	2.16	10.26	SC
LaMnO ₃	3.880	1.60	9.70	Insulator
(LaSr)MnO ₃	3.860	0.98	9.07	Metal
LaNiO ₃	3.859	0.98	9.07	Metal
NdGaO ₃	3.841	0.51	8.61	Insulator
LaAlO ₃	3.793	-0.75	7.35	Insulator
RE(Ti,Zr)O _{3,δ}	3.6-3.9			

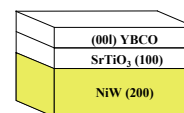
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U. S. DEPARTMENT OF ENERGY



Proposed all-solution structure: YBCO//SrTiO₃//NiW

Why SrTiO₃?

- Single non-vacuum buffer layer
 - alternative: seed+diffusion barrier+cap
 - others: Gd₂Ce₂O₇, Gd₂Zr₂O₇, BaZrO₃
 - can be grown thick (0.2 μm/layer)

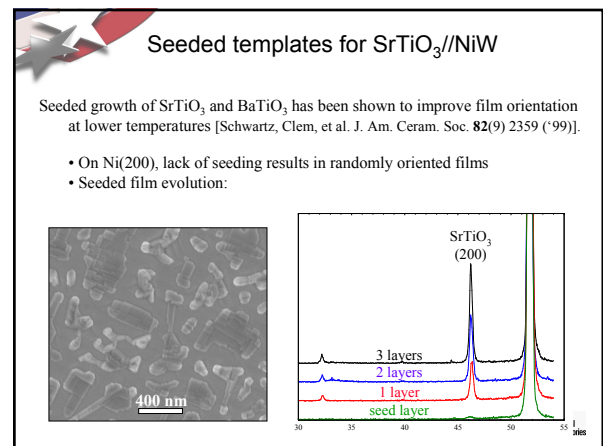
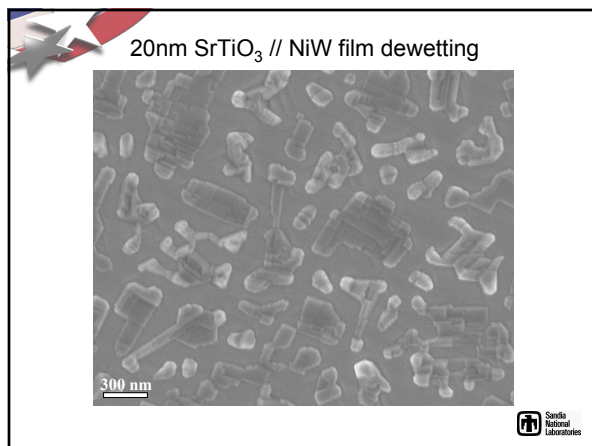
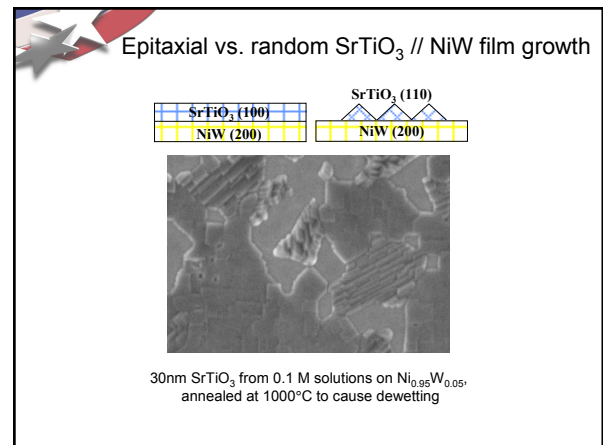
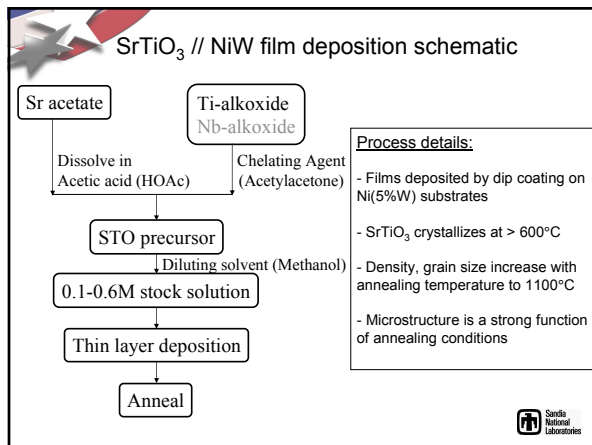
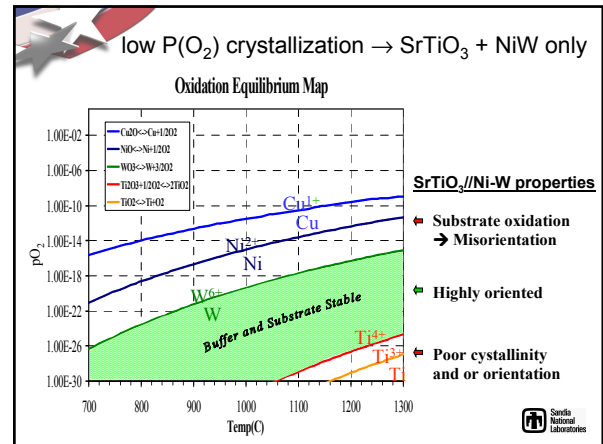
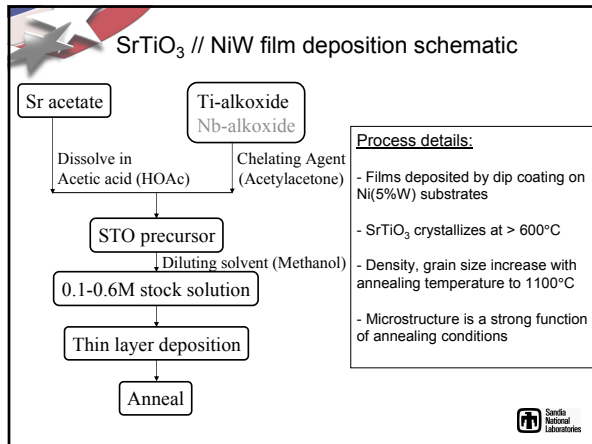


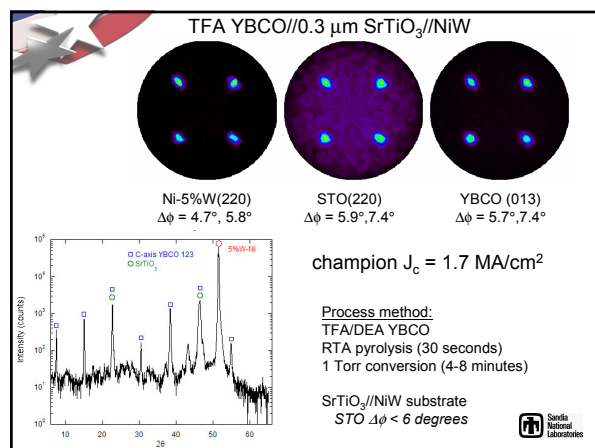
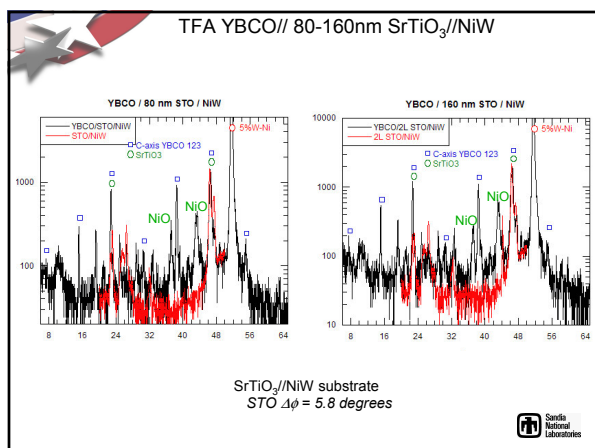
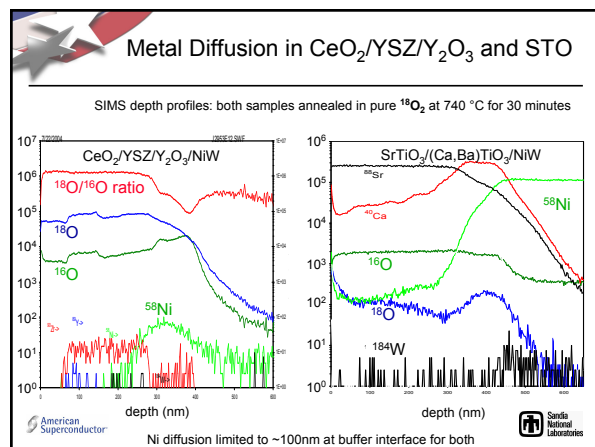
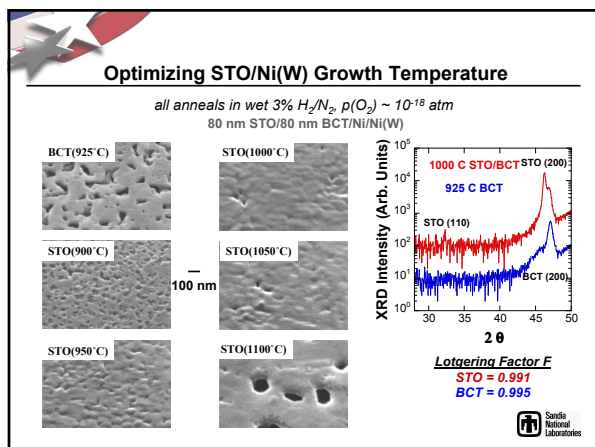
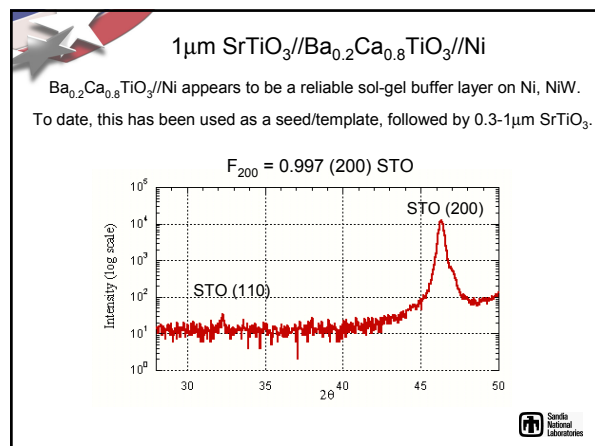
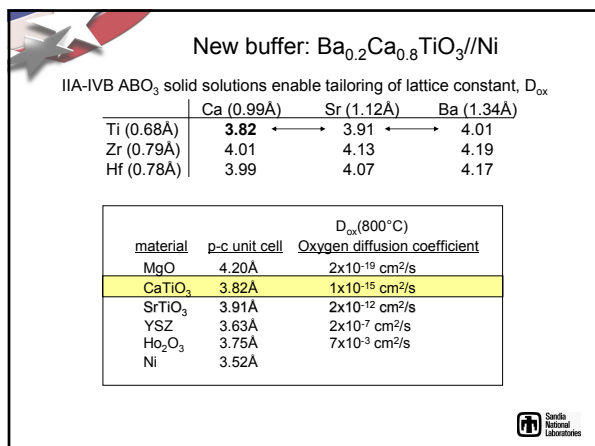
- Direct compatibility with BaF₂ YBCO
 - well-known compatibility of TFA YBCO with single crystal STO substrates
 - not reactive with water vapor, BaF₂
 - low STO oxygen diffusion rate
 - 0.3 μm STO → no NiO at 780°C, 20 min

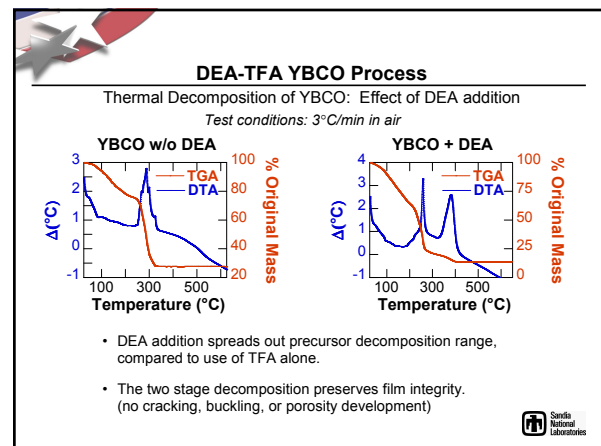
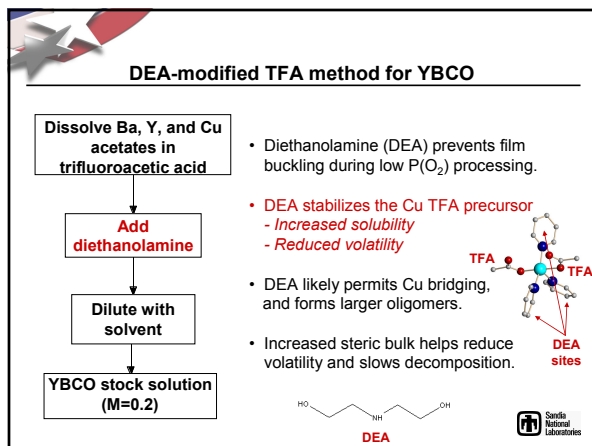
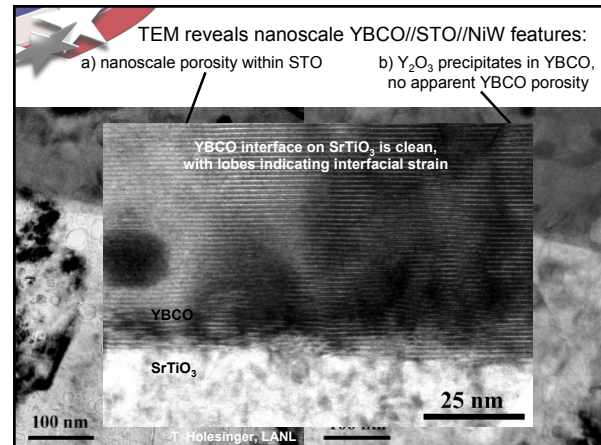
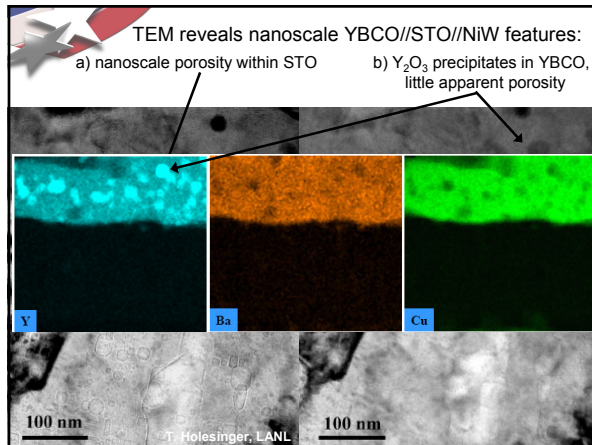
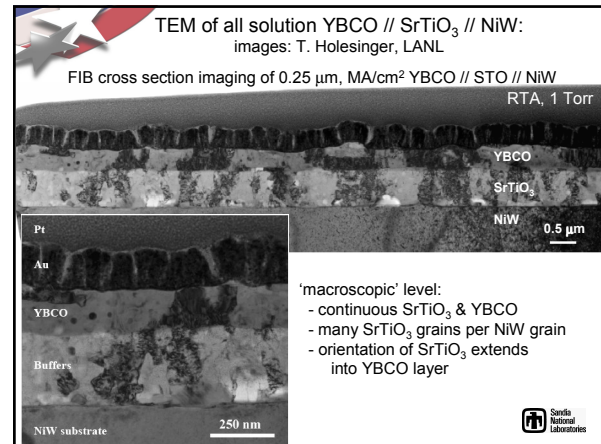
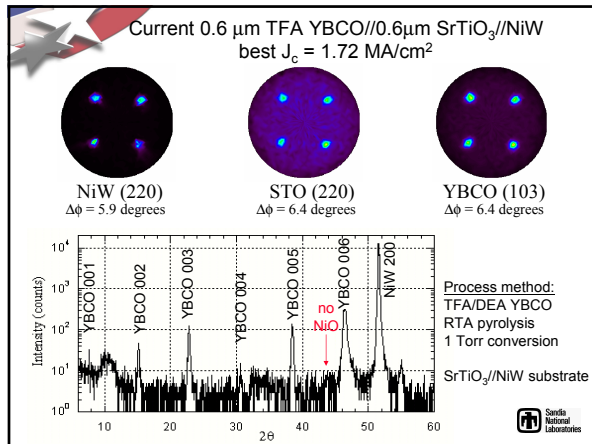
~780°C, ↓ O₂, H₂O

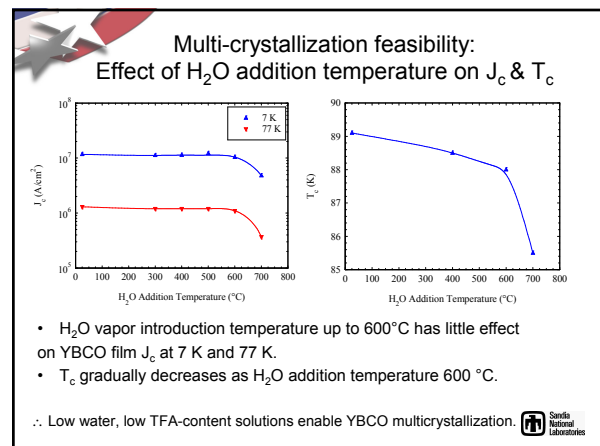
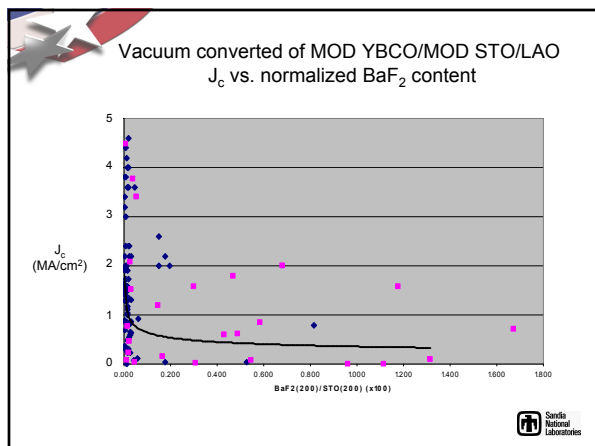
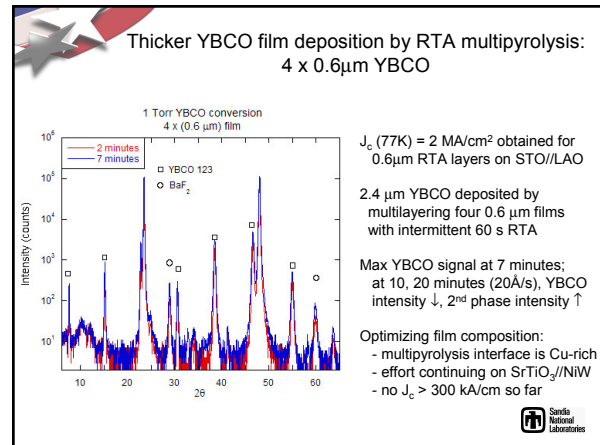
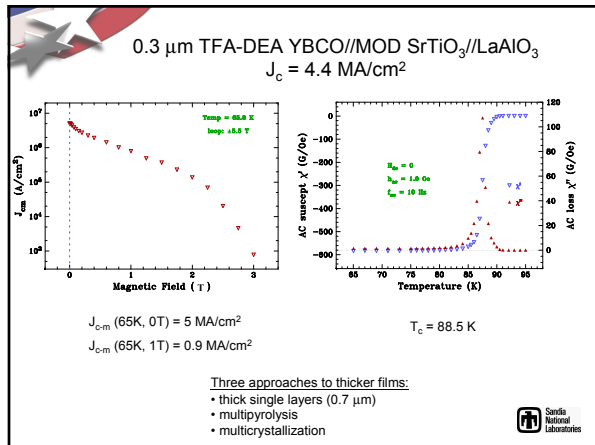
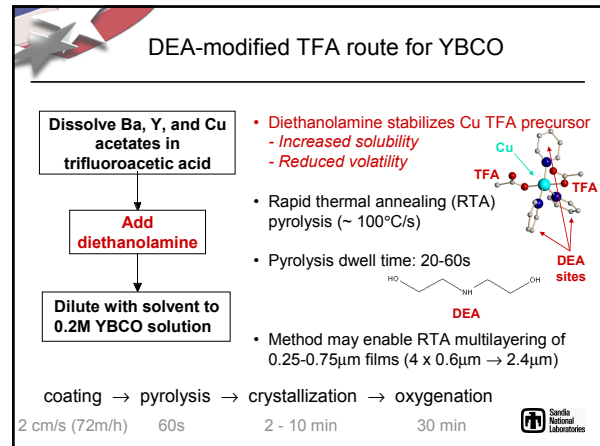
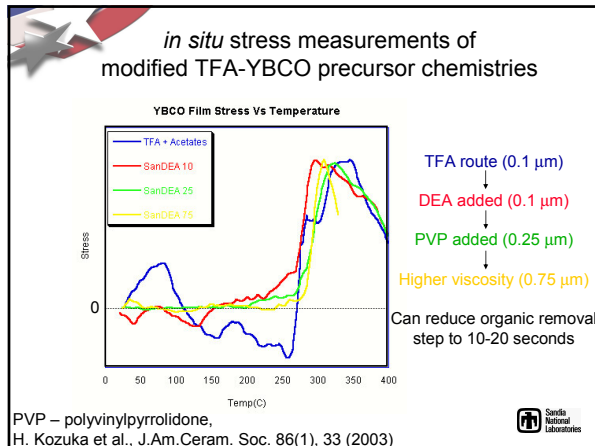
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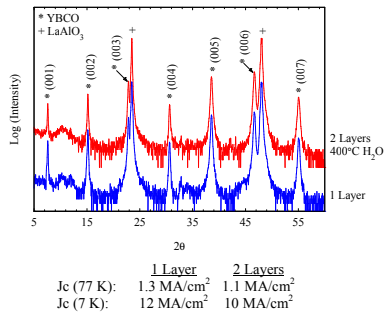




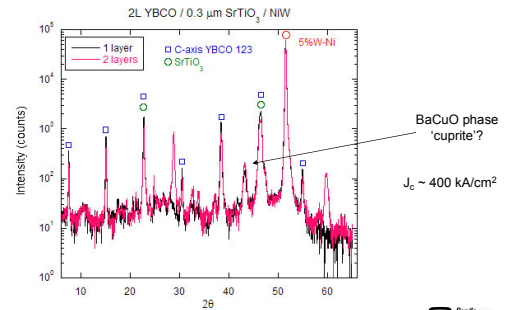




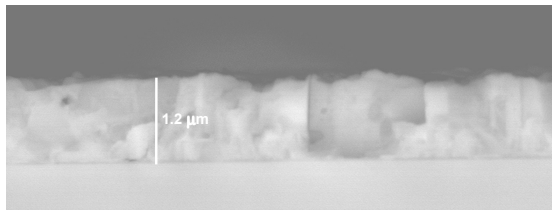
Ex-situ crystallization of a second YBCO layer by delayed water introduction



Multicrystallization of TFA-DEA YBCO on STO/NiW



Thick (1.2 μm) TFA-DEA YBCO from multicrystallized layers (not optimized)



t = 1.2 μm, J_c < 1 MA/cm²

[Cu] being optimized and extended to 4 x 0.6 μm



Summary

All-solution deposited coated conductors are feasible:

- 1) Dense SrTiO₃ may be deposited on NiW at 1000°C at low PO₂
- 2) Metal and oxygen diffusion are limited by STO or CeO₂/YSZ/Y₂O₃
- 3) TFA/DEA YBCO may be RTA annealed and converted at 20 Å/s
- 4) All-solution YBCO//STO//NiW : 0.6μm, J_c up to 1.72 MA/cm²
- 5) Multilayering+vacuum conversion an approach to 2μm+ TFA films

Key work: optimizing multilayered YBCO on thick (0.25μm) STO

